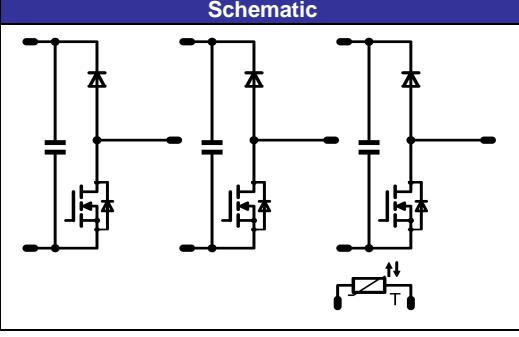


flow3xBOOST0-SiC		1200V/80mΩ
Features	<ul style="list-style-type: none"> • SiC-Power MOSFET's and Schottky Diodes • 3 channel boost topology • Ultra Low Inductance with integrated DC-capacitors • Switching frequency >100kHz • Temperature sensor 	
Target Applications	<ul style="list-style-type: none"> • solar inverter • Power Supply 	
Types	<ul style="list-style-type: none"> • 10-PZ123BA080ME-M909L18Y 	

Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
T₁, T₂, T₃, T₄, T₅, T₆				
Drain to source breakdown voltage	V _{DS}		1200	V
DC drain current	I _D	T _j =T _j max T _h =80°C T _c =80°C	17 21	A
Pulsed drain current	I _{Dpulse}	t _p limited by T _j max	60	A
Power dissipation	P _{tot}	T _j =T _j max T _h =80°C T _c =80°C	41 62	W
Gate-source peak voltage	V _{GS}		-10/25	V
Maximum Junction Temperature	T _j max		150	°C

D₁, D₂, D₃, D₄, D₅, D₆

Peak Repetitive Reverse Voltage	V _{RRM}		1200	V
Forward average current	I _{FAV}	T _j =T _j max T _h =80°C T _c =80°C	17 21	A
Non-Repetitive Peak Forward Surge Current	I _{FSM}	t _p =10ms T _j =25°C	92	A
Repetitive Peak Forward Surge Current	I _{FRM}	t _p limited by T _j max	52	A
Power dissipation per Diode	P _{tot}	T _j =T _j max T _h =80°C T _c =80°C	50 76	W
Maximum Junction Temperature	T _j max		175	°C

Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
-----------	--------	-----------	-------	------

C1, C2, C3

Max.DC voltage	V _{MAX}	T _c =25°C	1000	V
----------------	------------------	----------------------	------	---

Thermal Properties

Storage temperature	T _{stg}		-40...+125	°C
Operation temperature under switching condition	T _{op}		-40...+(T _{jmax} - 25)	°C

Insulation Properties

Insulation voltage		t=2s	DC voltage	4000	V
Creepage distance				min 12,7	mm
Clearance				min 9,9	mm

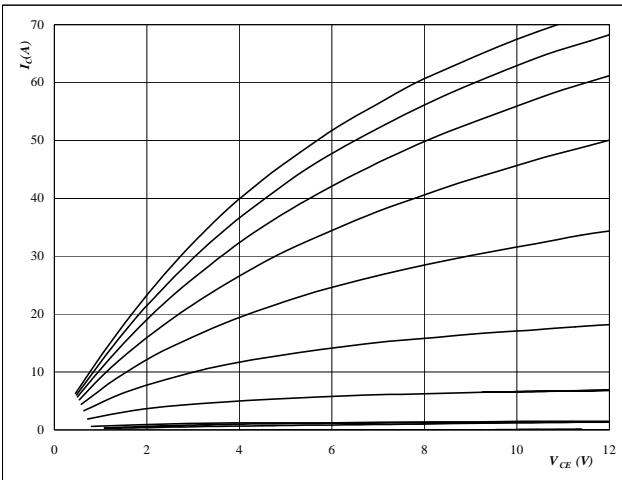
Characteristic Values

Parameter	Symbol	Conditions					Value			Unit	
			V_{GE} [V] or V_{GS} [V]	V_r [V] or V_{CE} [V] or V_{DS} [V]	I_c [A] or I_F [A] or I_B [A]	T_j	Min	Typ	Max		
T1, T2, T3, T4, T5, T6											
Static drain to source ON resistance	$R_{DS(on)}$		20		20	$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		0,08 0,14		Ω	
Gate threshold voltage	$V_{(GS)th}$	$V_{DS} = V_{GS}$		10	0,001	$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$	1,7	2,2		V	
Gate to Source Leakage Current	I_{gss}		20	0		$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$			250	nA	
Zero Gate Voltage Drain Current	I_{dss}		0	1200		$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$			100	μA	
Internal Gate Resistance	R_G	$f=1\text{MHz}; V_{AC}=25\text{mV}$						4,6		Ω	
Turn On Delay Time	$t_{d(ON)}$	$R_{goff}=4\ \Omega$ $R_{gon}=4\ \Omega$	16	700	16	$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		12 10		ns	
Rise Time	t_r					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		5 5			
Turn off delay time	$t_{d(OFF)}$					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		36 39			
Fall time	t_f					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		16 18			
Turn-on energy loss per pulse	E_{on}					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		0,126 0,108		mWs	
Turn-off energy loss per pulse	E_{off}					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		0,051 0,050			
Total gate charge	Q_g							49,2			
Gate to source charge	Q_{gs}	0/20	800	20	$T_j=25^\circ\text{C}$			10,8		nC	
Gate to drain charge	Q_{gd}							18			
Input capacitance	C_{iss}							950			
Output capacitance	C_{oss}	$f=1\text{MHz}$	0	1000				80		pF	
Reverse transfer capacitance	C_{rss}							6,5			
Thermal resistance chip to heatsink per chip	R_{thJH}	Phase-Change Material						1,72		K/W	
D1, D2, D3, D4, D5, D6											
Forward voltage	V_F				10	$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		1,46 1,80	1,8	V	
Reverse leakage current	I_{rm}			1200		$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$			300	μA	
Peak recovery current	I_{RRM}	$R_{gon}=4\ \Omega$	16	700	16	$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		17 18		A	
Reverse recovery time	t_{rr}					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		10 11		ns	
Reverse recovery charge	Q_{rr}					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		0,102 0,103		μC	
Reverse recovered energy	E_{rec}					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		0,028 0,031		mWs	
Peak rate of fall of recovery current	$d(i_{rec})/\max dt$					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		3666 3626		$\text{A}/\mu\text{s}$	
Thermal resistance chip to heatsink per chip	R_{thJH}	Phase-Change Material						1,88		K/W	
C1, C2, C3											
C value	C							47		nF	
Thermistor											
Rated resistance	R					$T=25^\circ\text{C}$		22000		Ω	
Deviation of R25	$\Delta R/R$	$R_{100}=1486\ \Omega$				$T=25^\circ\text{C}$	-5		5	%	
Power dissipation	P					$T=25^\circ\text{C}$		200		mW	
Power dissipation constant						$T=25^\circ\text{C}$		2		mW/K	
B-value	$B_{(25/50)}$	Tol. $\pm 3\%$				$T=25^\circ\text{C}$		3950		K	
B-value	$B_{(25/100)}$	Tol. $\pm 3\%$				$T=25^\circ\text{C}$		3996		K	
Vincotech NTC Reference									B		

T1, T2, T3, T4, T5, T6 / D1, D2, D3, D4, D5, D6

Figure 1
T1, T2, T3, T4, T5, T6 MOSFET
Typical output characteristics

$$I_D = f(V_{DS})$$


At

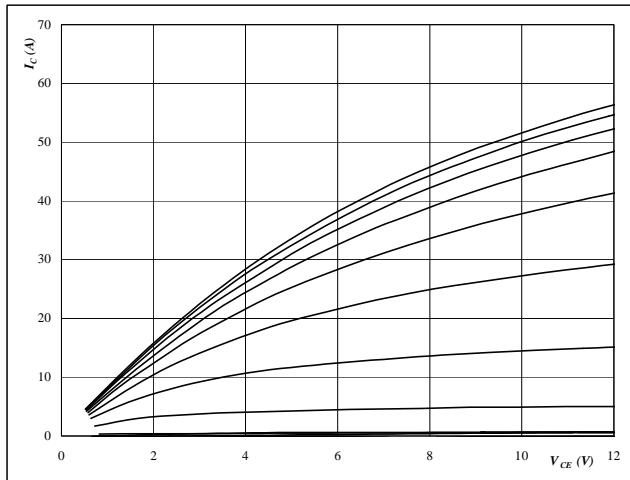
$$t_p = 250 \mu\text{s}$$

$$T_j = 25^\circ\text{C}$$

 V_{GS} from 0 V to 20 V in steps of 2 V

Figure 2
T1, T2, T3, T4, T5, T6 MOSFET
Typical output characteristics

$$I_D = f(V_{DS})$$


At

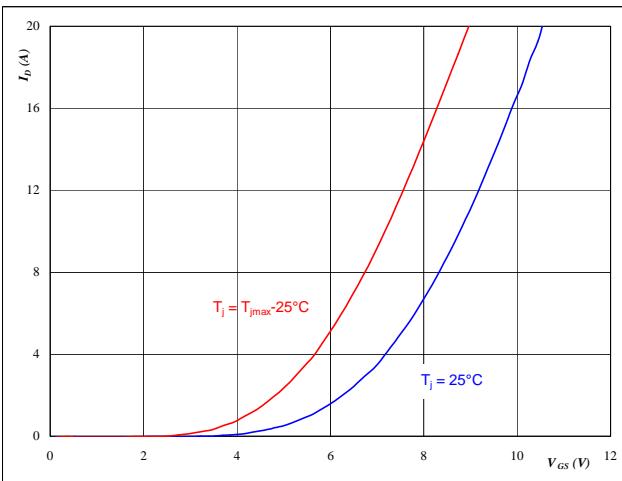
$$t_p = 250 \mu\text{s}$$

$$T_j = 126^\circ\text{C}$$

 V_{GS} from 0 V to 20 V in steps of 2 V

Figure 3
T1, T2, T3, T4, T5, T6 MOSFET
Typical transfer characteristics

$$I_D = f(V_{GS})$$

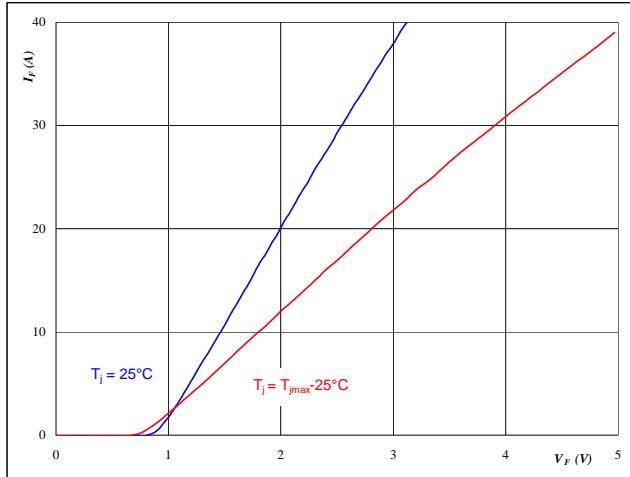

At

$$t_p = 250 \mu\text{s}$$

$$V_{DS} = 10 \text{ V}$$

Figure 4
D1, D2, D3, D4, D5, D6 FWD
Typical diode forward current as
a function of forward voltage

$$I_F = f(V_F)$$

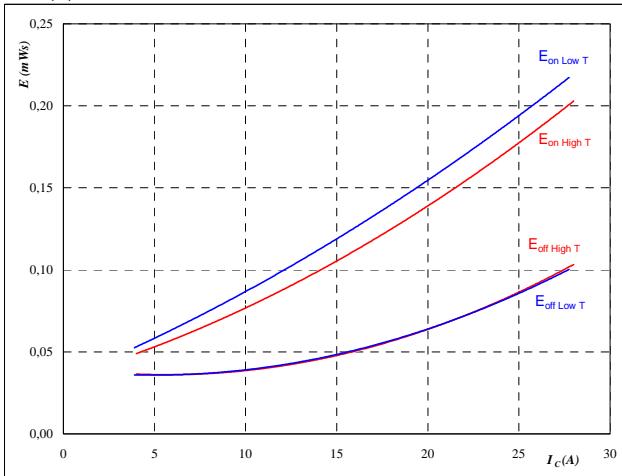

At

$$t_p = 250 \mu\text{s}$$

T1, T2, T3, T4, T5, T6 / D1, D2, D3, D4, D5, D6

Figure 5
T1, T2, T3, T4, T5, T6 MOSFET
**Typical switching energy losses
as a function of collector current**

$$E = f(I_D)$$

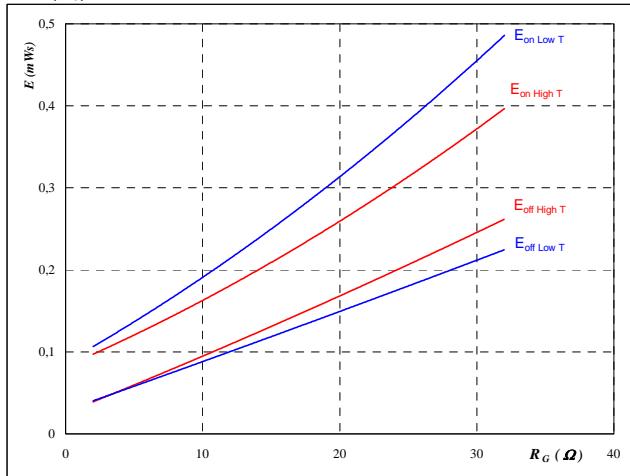


With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 700 \quad \text{V} \\ V_{GS} &= 16 \quad \text{V} \\ R_{gon} &= 4 \quad \Omega \\ R_{goff} &= 4 \quad \Omega \end{aligned}$$

Figure 6
T1, T2, T3, T4, T5, T6 MOSFET
**Typical switching energy losses
as a function of gate resistor**

$$E = f(R_G)$$

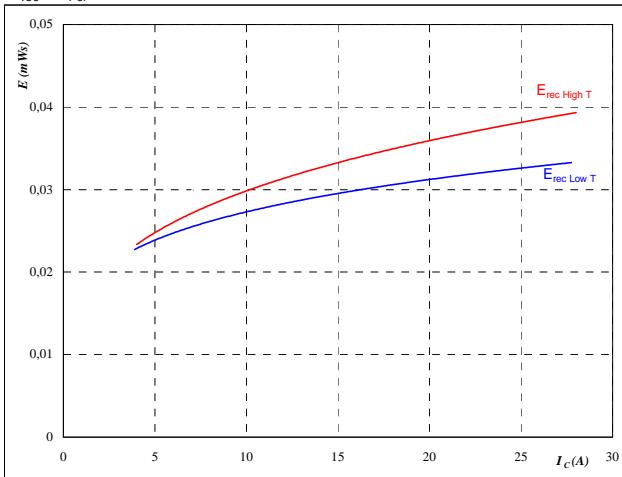


With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 700 \quad \text{V} \\ V_{GS} &= 16 \quad \text{V} \\ I_D &= 16 \quad \text{A} \end{aligned}$$

Figure 7
D1, D2, D3, D4, D5, D6 FWD
**Typical reverse recovery energy loss
as a function of collector (drain) current**

$$E_{rec} = f(I_c)$$

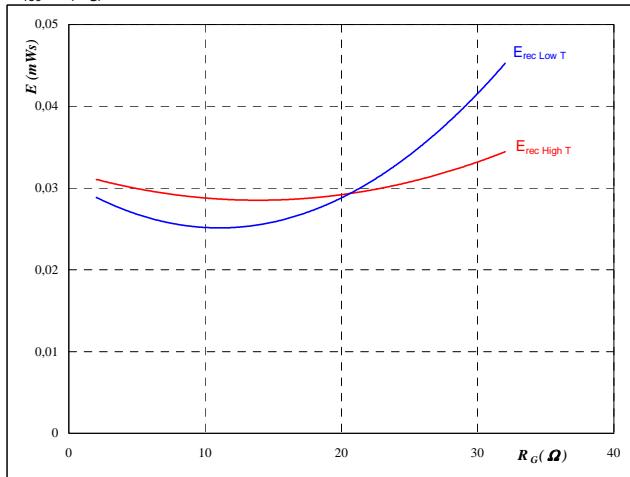


With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 700 \quad \text{V} \\ V_{GS} &= 16 \quad \text{V} \\ R_{gon} &= 4 \quad \Omega \\ R_{goff} &= 4 \quad \Omega \end{aligned}$$

Figure 8
D1, D2, D3, D4, D5, D6 FWD
**Typical reverse recovery energy loss
as a function of gate resistor**

$$E_{rec} = f(R_G)$$



With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 700 \quad \text{V} \\ V_{GS} &= 16 \quad \text{V} \\ I_D &= 16 \quad \text{A} \end{aligned}$$

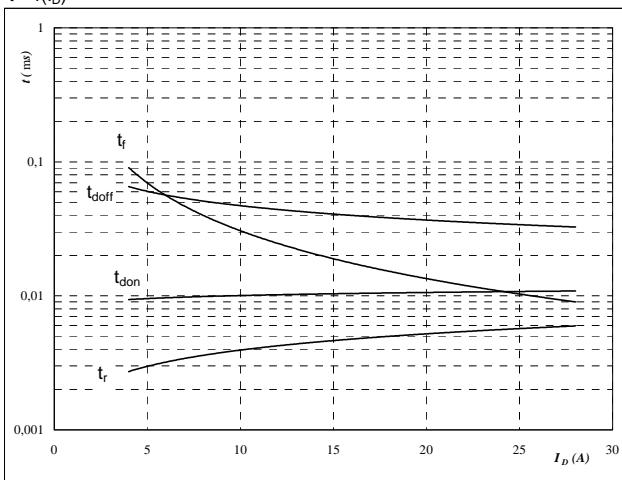
T1, T2, T3, T4, T5, T6 / D1, D2, D3, D4, D5, D6

Figure 9

T1, T2, T3, T4, T5, T6 MOSFET

Typical switching times as a function of collector current

$t = f(I_D)$



With an inductive load at

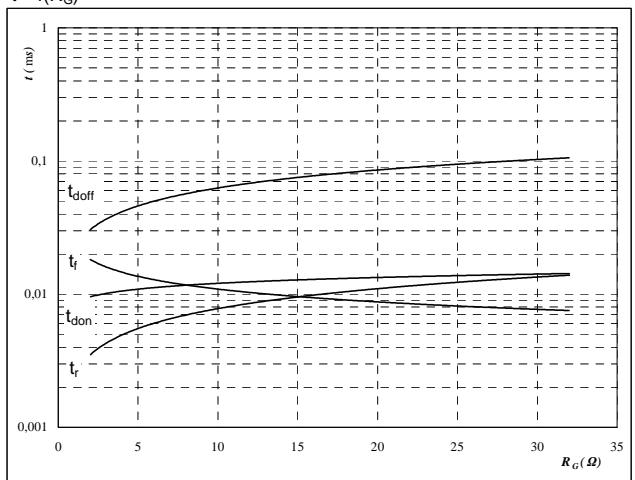
$T_j =$	125	°C
$V_{DS} =$	700	V
$V_{GS} =$	16	V
$R_{gon} =$	4	Ω
$R_{goff} =$	4	Ω

Figure 10

T1, T2, T3, T4, T5, T6 MOSFET

Typical switching times as a function of gate resistor

$t = f(R_G)$



With an inductive load at

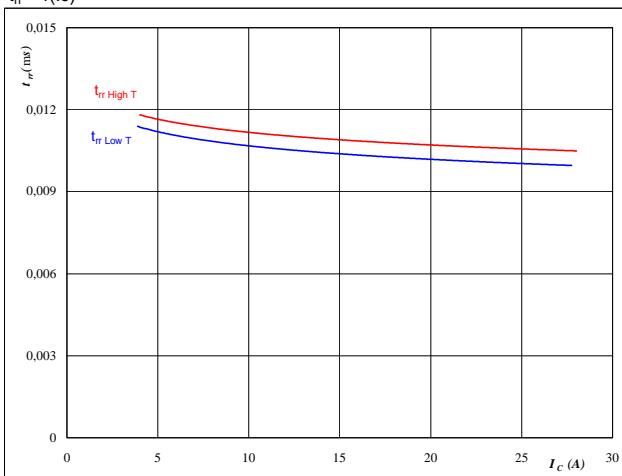
$T_j =$	125	°C
$V_{DS} =$	700	V
$V_{GS} =$	16	V
$I_C =$	16	A

Figure 11

D1, D2, D3, D4, D5, D6 FWD

Typical reverse recovery time as a function of collector current

$t_{rr} = f(I_C)$



At

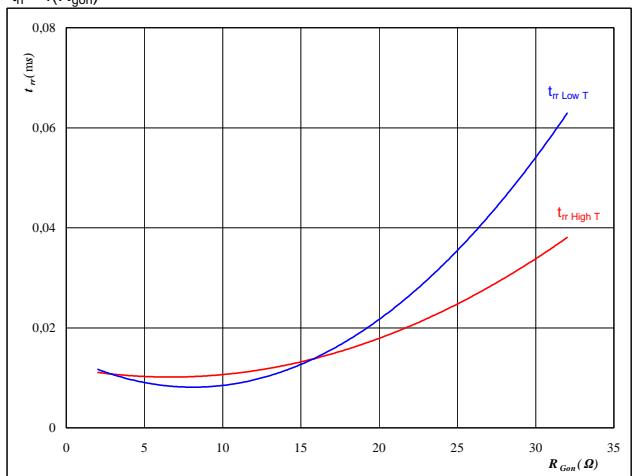
$T_j =$	25/125	°C
$V_{CE} =$	700	V
$V_{GE} =$	16	V
$R_{gon} =$	4	Ω

Figure 12

D1, D2, D3, D4, D5, D6 FWD

Typical reverse recovery time as a function of IGBT turn on gate resistor

$t_{rr} = f(R_{Gon})$



At

$T_j =$	25/125	°C
$V_R =$	700	V
$I_F =$	16	A
$V_{GS} =$	16	V

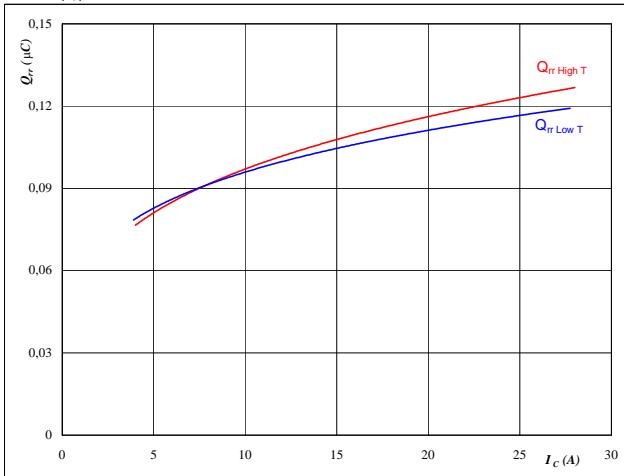
T1, T2, T3, T4, T5, T6 / D1, D2, D3, D4, D5, D6

Figure 13

D1, D2, D3, D4, D5, D6 FWD

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_C)$$


At

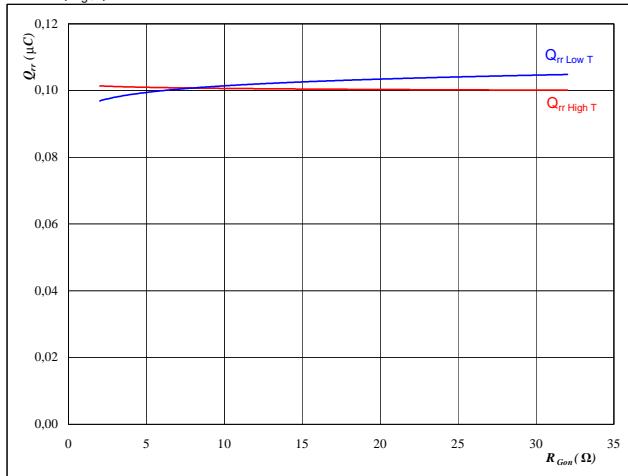
$T_j = 25/125 \quad ^\circ\text{C}$
 $V_{CE} = 700 \quad \text{V}$
 $V_{GE} = 16 \quad \text{V}$
 $R_{gon} = 4 \quad \Omega$

Figure 14

D1, D2, D3, D4, D5, D6 FWD

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$


At

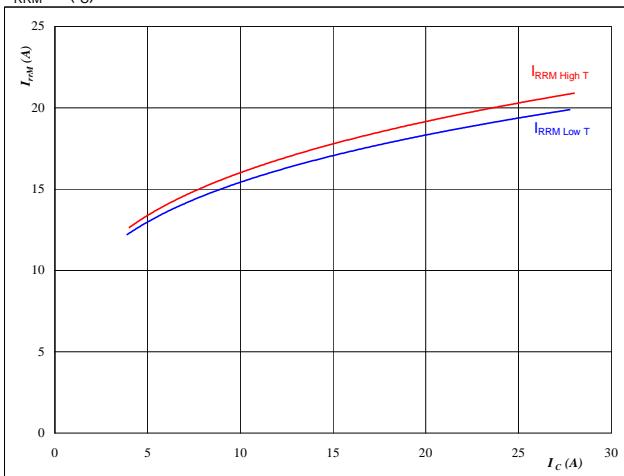
$T_j = 25/125 \quad ^\circ\text{C}$
 $V_R = 700 \quad \text{V}$
 $I_F = 16 \quad \text{A}$
 $V_{GS} = 16 \quad \text{V}$

Figure 15

D1, D2, D3, D4, D5, D6 FWD

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_C)$$


At

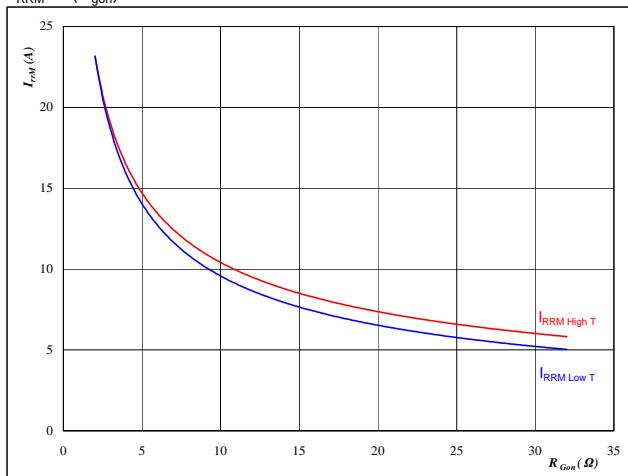
$T_j = 25/125 \quad ^\circ\text{C}$
 $V_{CE} = 700 \quad \text{V}$
 $V_{GE} = 16 \quad \text{V}$
 $R_{gon} = 4 \quad \Omega$

Figure 16

D1, D2, D3, D4, D5, D6 FWD

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$


At

$T_j = 25/125 \quad ^\circ\text{C}$
 $V_R = 700 \quad \text{V}$
 $I_F = 16 \quad \text{A}$
 $V_{GS} = 16 \quad \text{V}$

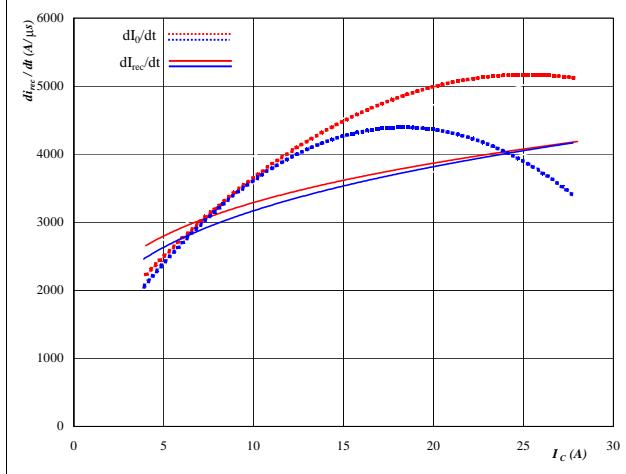
T1, T2, T3, T4, T5, T6 / D1, D2, D3, D4, D5, D6

Figure 17

D1, D2, D3, D4, D5, D6 FWD

**Typical rate of fall of forward
and reverse recovery current as a
function of collector current**

$$dI_0/dt, dI_{rec}/dt = f(I_C)$$


At

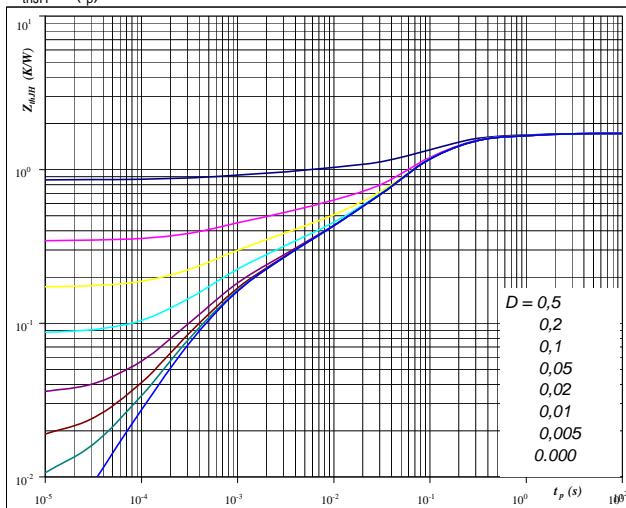
$T_j = 25/125 \quad {}^\circ\text{C}$
 $V_{CE} = 700 \quad \text{V}$
 $V_{GE} = 16 \quad \text{V}$
 $R_{Gon} = 4 \quad \Omega$

Figure 19

T1, T2, T3, T4, T5, T6 MOSFET

**IGBT/MOSFET transient thermal impedance
as a function of pulse width**

$$Z_{thJH} = f(t_p)$$


At

$D = t_p / T$
 $R_{thJH} = 1,72 \quad \text{K/W}$

IGBT thermal model values

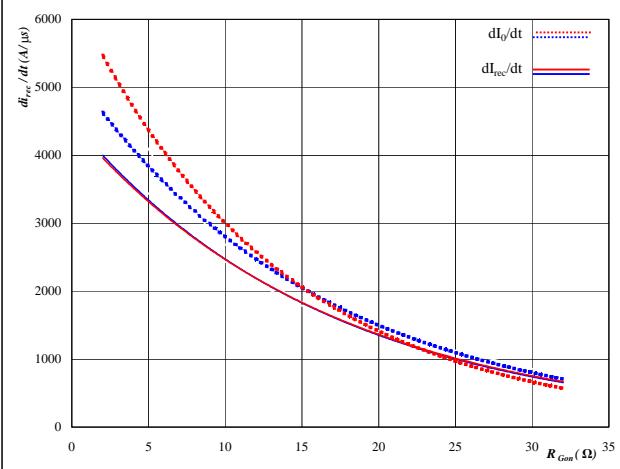
R (C/W)	Tau (s)
1,42E-01	1,02E+00
7,14E-01	1,29E-01
5,71E-01	5,47E-02
1,68E-01	3,53E-03
1,23E-01	5,32E-04

Figure 18

D1, D2, D3, D4, D5, D6 FWD

**Typical rate of fall of forward
and reverse recovery current as a
function of IGBT turn on gate resistor**

$$dI_0/dt, dI_{rec}/dt = f(R_{gon})$$


At

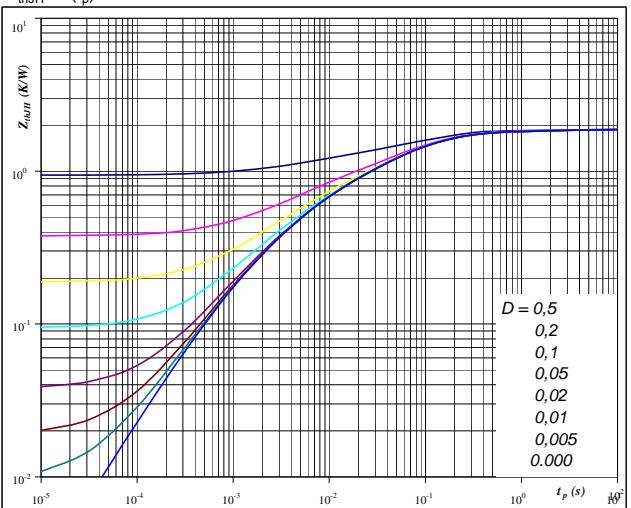
$T_j = 25/125 \quad {}^\circ\text{C}$
 $V_R = 700 \quad \text{V}$
 $I_F = 16 \quad \text{A}$
 $V_{GS} = 16 \quad \text{V}$

Figure 20

D1, D2, D3, D4, D5, D6 FWD

**FWD transient thermal impedance
as a function of pulse width**

$$Z_{thJH} = f(t_p)$$

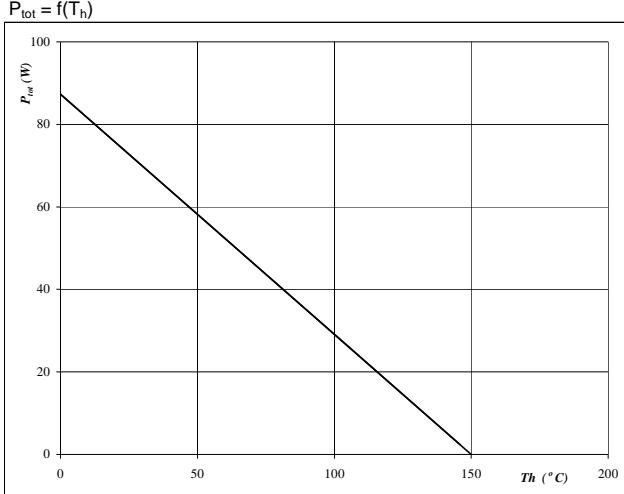

At

$D = t_p / T$
 $R_{thJH} = 1,88 \quad \text{K/W}$

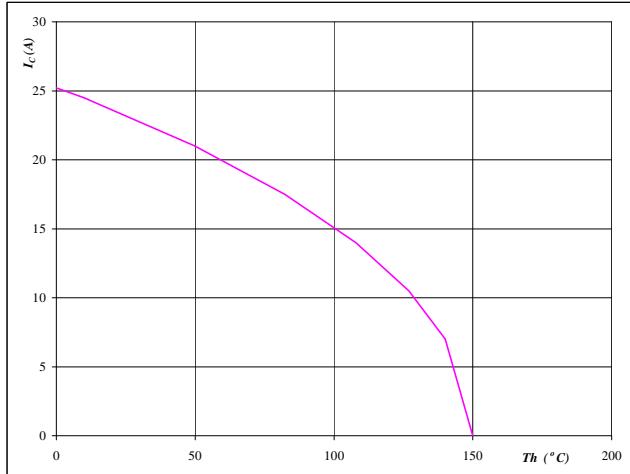
FWD thermal model values

R (C/W)	Tau (s)
5,58E-02	6,96E+00
1,47E-01	5,43E-01
8,94E-01	7,92E-02
4,33E-01	1,33E-02
2,94E-01	3,03E-03
5,99E-02	6,32E-04

T1, T2, T3, T4, T5, T6 / D1, D2, D3, D4, D5, D6

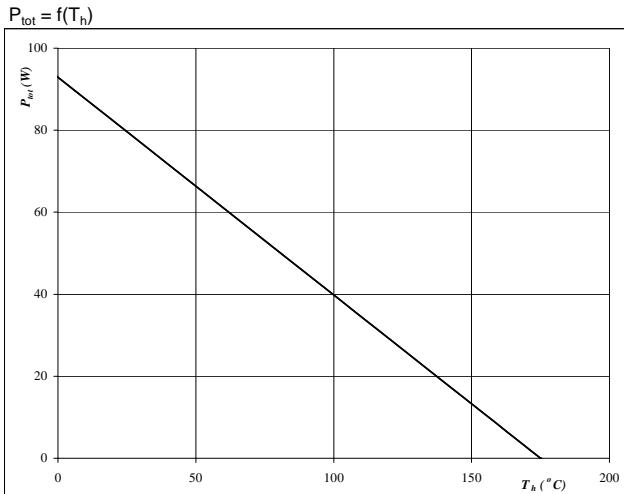
Figure 21
T1, T2, T3, T4, T5, T6 MOSFET
Power dissipation as a function of heatsink temperature
 $P_{\text{tot}} = f(T_h)$

At

T_j = 150 °C

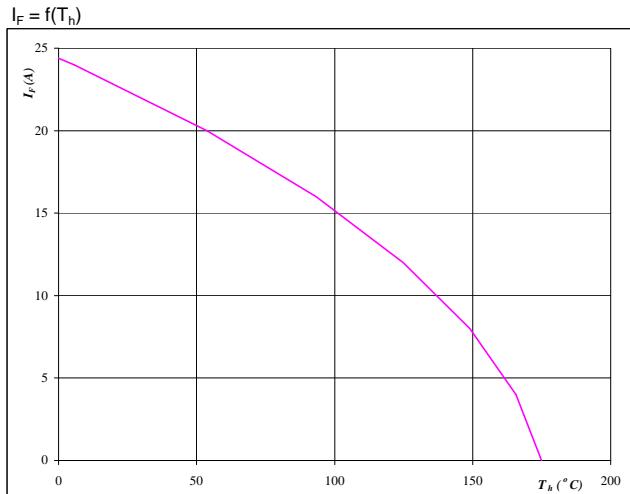
Figure 22
T1, T2, T3, T4, T5, T6 MOSFET
Collector/Drain current as a function of heatsink temperature
 $I_C = f(T_h)$

At

T_j = 150 °C

V_{GS} = 20 V

Figure 23
D1, D2, D3, D4, D5, D6 FWD
Power dissipation as a function of heatsink temperature
 $P_{\text{tot}} = f(T_h)$

At

T_j = 175 °C

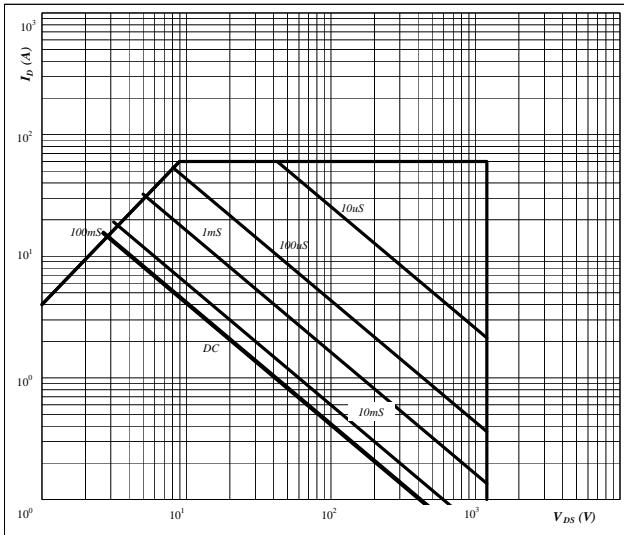
Figure 24
D1, D2, D3, D4, D5, D6 FWD
Forward current as a function of heatsink temperature
 $I_F = f(T_h)$

At

T_j = 175 °C

T1, T2, T3, T4, T5, T6 / D1, D2, D3, D4, D5, D6

Figure 25
T1, T2, T3, T4, T5, T6 MOSFET
Safe operating area as a function
of drain-source voltage

$$I_D = f(V_{DS})$$


At

D = single pulse

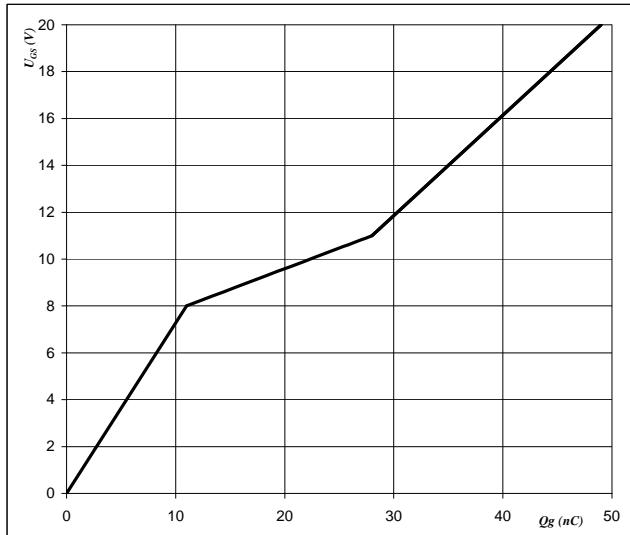
T_h = 80 °C

V_{GS} = 16 V

T_j = T_{jmax} °C

Figure 26
T1, T2, T3, T4, T5, T6 MOSFET
Gate voltage vs Gate charge

$$V_{GS} = f(Qg)$$


At

I_{DS} = 20 A

V_{DS} = 800 V

I_{GS} = 10 mA

T_j = 25 °C

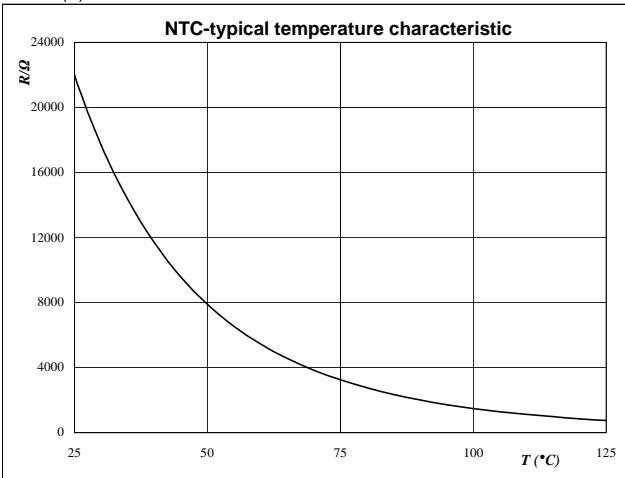
Thermistor

Figure 1

Thermistor

Typical NTC characteristic
as a function of temperature

$$R_T = f(T)$$



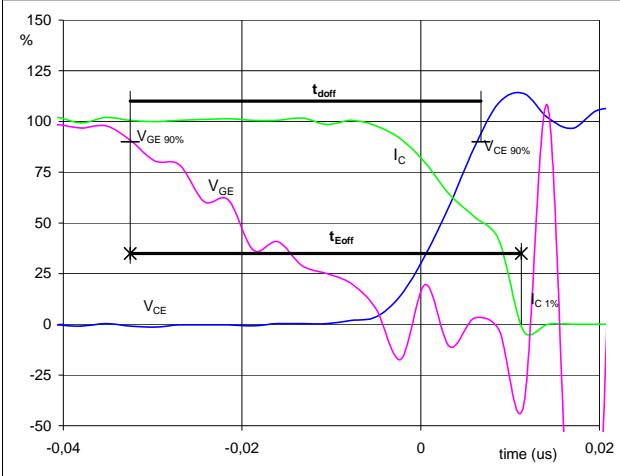
Switching Definitions BOOST

General conditions

T_j	=	125 °C
R_{gon}	=	4 Ω
R_{goff}	=	4 Ω

Figure 1
T1, T2, T3, T4, T5, T6 MOSFET

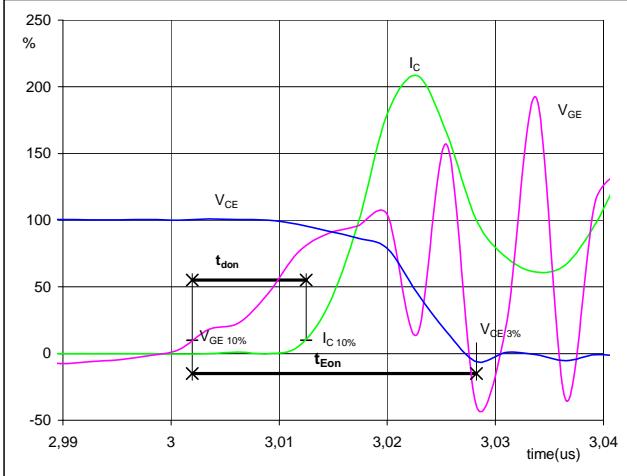
Turn-off Switching Waveforms & definition of t_{doff} , t_{Eoff}
 $(t_{Eoff} = \text{integrating time for } E_{off})$



$V_{GE}(0\%) = 0 \text{ V}$
 $V_{GE}(100\%) = 16 \text{ V}$
 $V_C(100\%) = 700 \text{ V}$
 $I_C(100\%) = 16 \text{ A}$
 $t_{doff} = 0,04 \mu\text{s}$
 $t_{Eoff} = 0,04 \mu\text{s}$

Figure 2
T1, T2, T3, T4, T5, T6 MOSFET

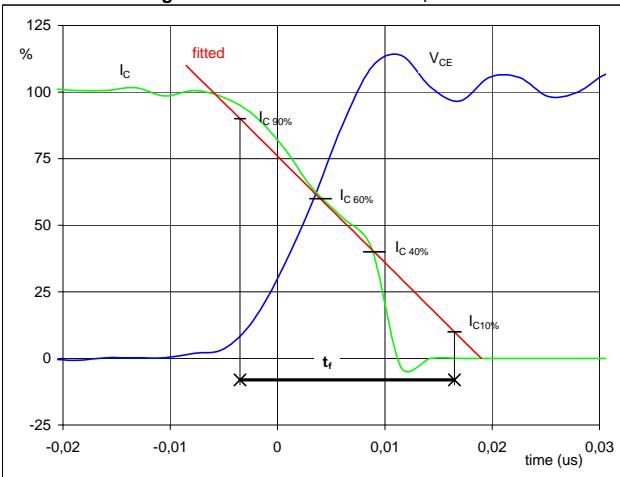
Turn-on Switching Waveforms & definition of t_{don} , t_{Eon}
 $(t_{Eon} = \text{integrating time for } E_{on})$



$V_{GE}(0\%) = 0 \text{ V}$
 $V_{GE}(100\%) = 16 \text{ V}$
 $V_C(100\%) = 700 \text{ V}$
 $I_C(100\%) = 16 \text{ A}$
 $t_{don} = 0,01 \mu\text{s}$
 $t_{Eon} = 0,03 \mu\text{s}$

Figure 3
T1, T2, T3, T4, T5, T6 MOSFET

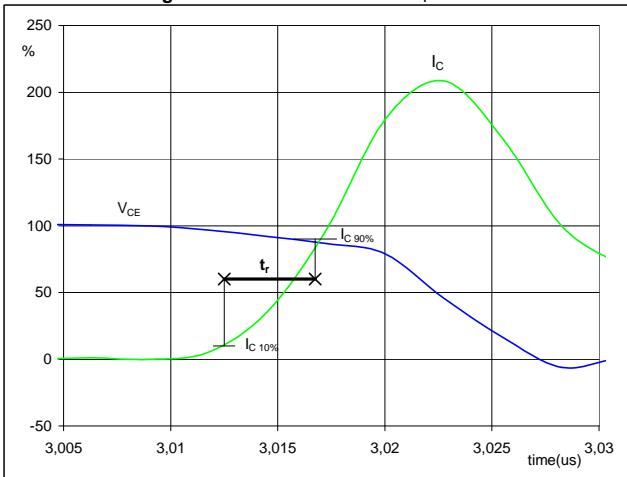
Turn-off Switching Waveforms & definition of t_f



$V_C(100\%) = 700 \text{ V}$
 $I_C(100\%) = 16 \text{ A}$
 $t_f = 0,02 \mu\text{s}$

Figure 4
T1, T2, T3, T4, T5, T6 MOSFET

Turn-on Switching Waveforms & definition of t_r

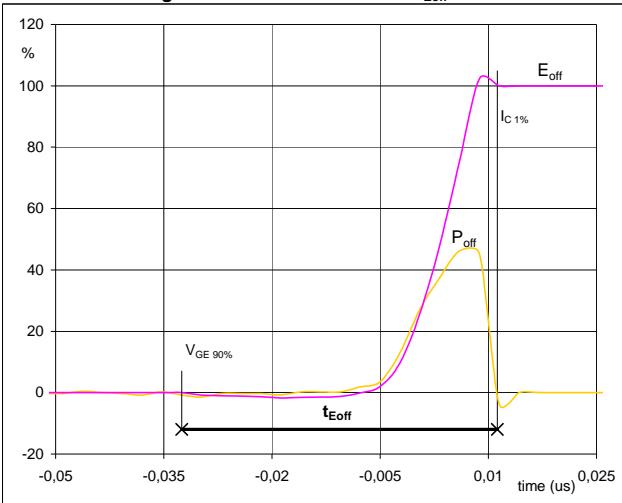


$V_C(100\%) = 700 \text{ V}$
 $I_C(100\%) = 16 \text{ A}$
 $t_r = 0,01 \mu\text{s}$

Switching Definitions BOOST

Figure 5

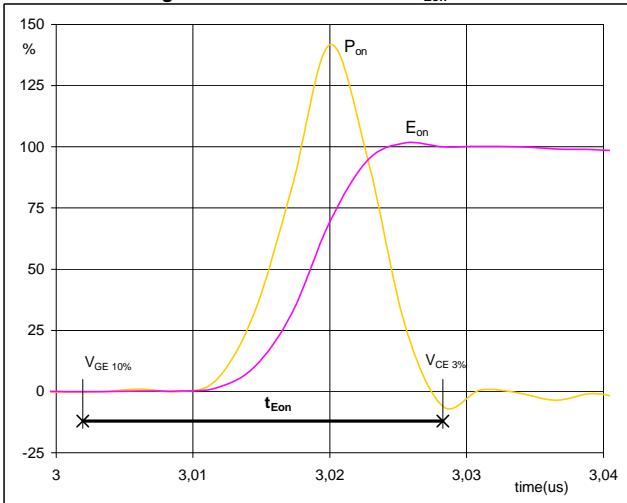
T1, T2, T3, T4, T5, T6 MOSFET

Turn-off Switching Waveforms & definition of t_{Eoff}


$P_{off} (100\%) = 11,12 \text{ kW}$
 $E_{off} (100\%) = 0,05 \text{ mJ}$
 $t_{Eoff} = 0,04 \text{ } \mu\text{s}$

Figure 6

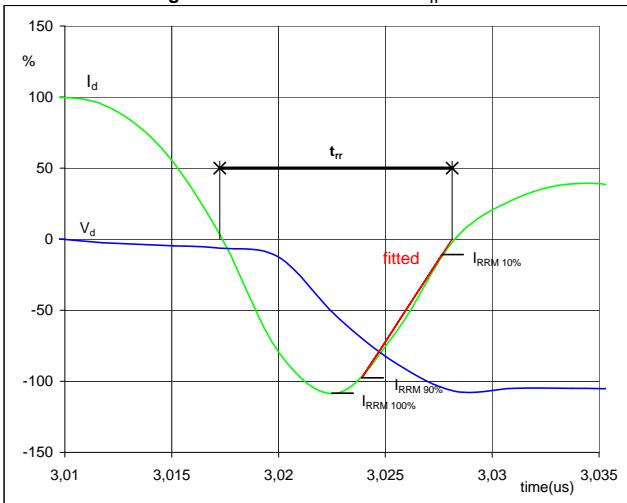
T1, T2, T3, T4, T5, T6 MOSFET

Turn-on Switching Waveforms & definition of t_{Eon}


$P_{on} (100\%) = 11,12 \text{ kW}$
 $E_{on} (100\%) = 0,11 \text{ mJ}$
 $t_{Eon} = 0,03 \text{ } \mu\text{s}$

Figure 7

D1, D2, D3, D4, D5, D6 FWD

Turn-off Switching Waveforms & definition of t_{rr}


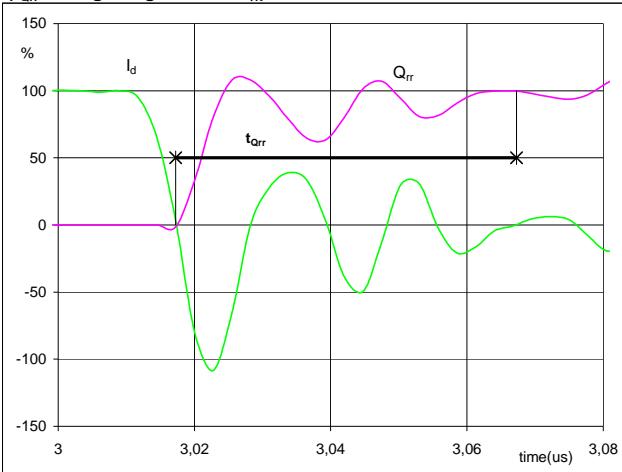
$V_d (100\%) = 700 \text{ V}$
 $I_d (100\%) = 16 \text{ A}$
 $I_{RRM} (100\%) = -18 \text{ A}$
 $t_{rr} = 0,01 \text{ } \mu\text{s}$

Switching Definitions BOOST

Figure 8

D1, D2, D3, D4, D5, D6 FWD

Turn-on Switching Waveforms & definition of t_{Qrr}
(t_{Qrr} = integrating time for Q_{rr})

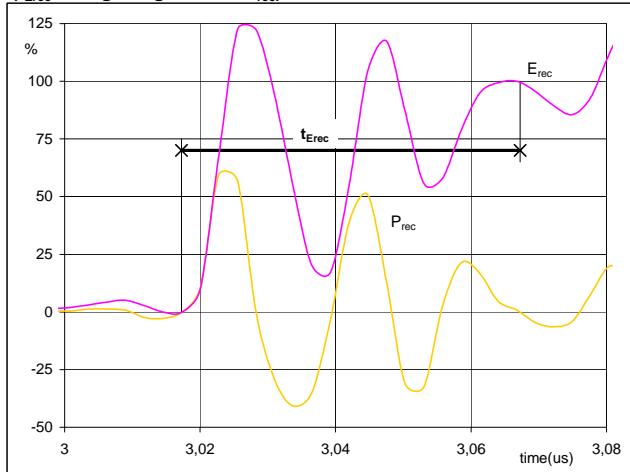


$I_d(100\%) = 16 \text{ A}$
 $Q_{rr}(100\%) = 0,10 \mu\text{C}$
 $t_{Qrr} = 0,05 \mu\text{s}$

Figure 10

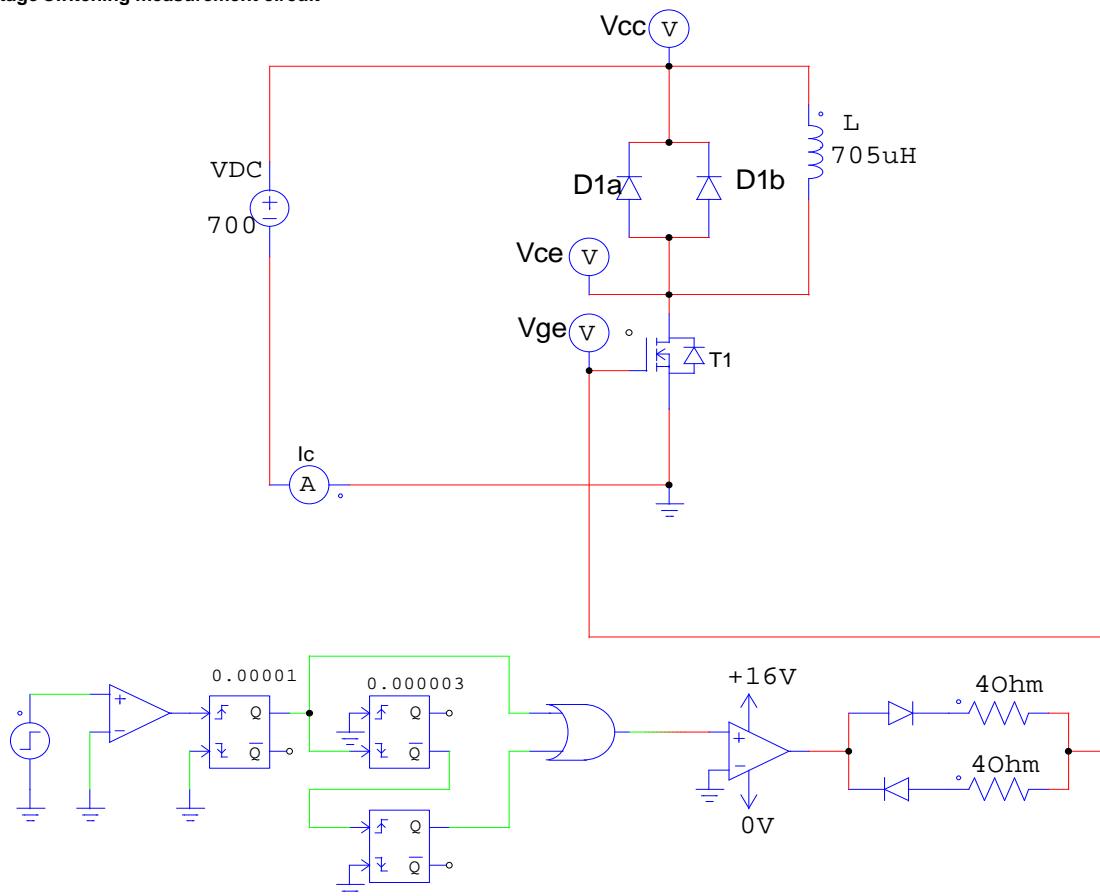
D1, D2, D3, D4, D5, D6 FWD

Turn-on Switching Waveforms & definition of t_{Erec}
(t_{Erec} = integrating time for E_{rec})



$P_{rec}(100\%) = 11,12 \text{ kW}$
 $E_{rec}(100\%) = 0,03 \text{ mJ}$
 $t_{Erec} = 0,05 \mu\text{s}$

Measurement circuit

Figure 11
BOOST stage switching measurement circuit


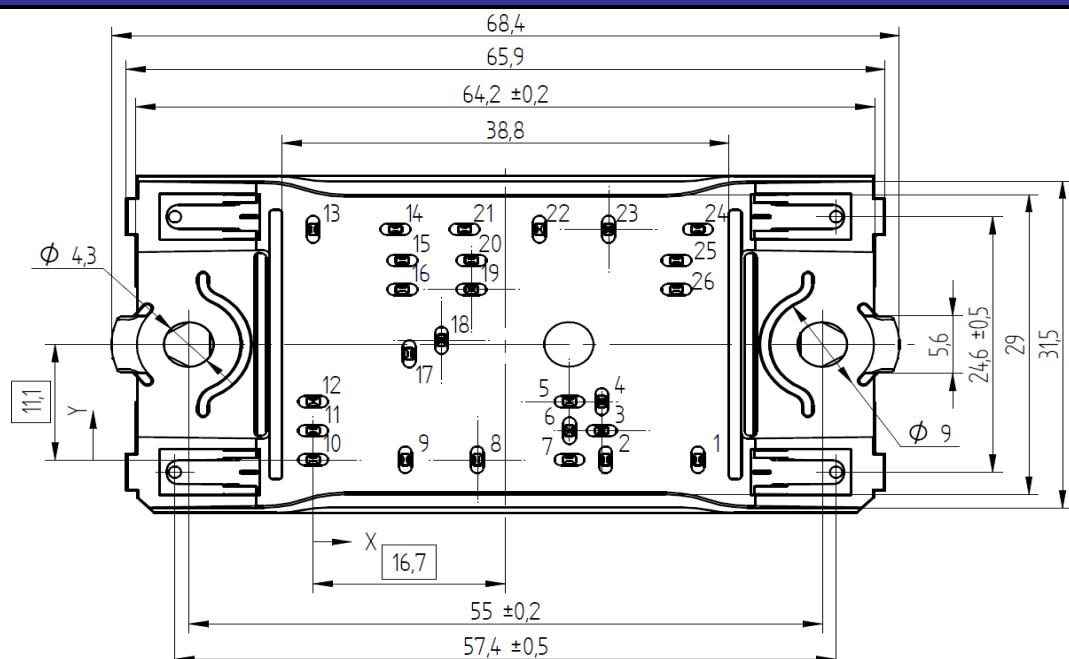
Ordering Code and Marking - Outline - Pinout

Ordering Code & Marking

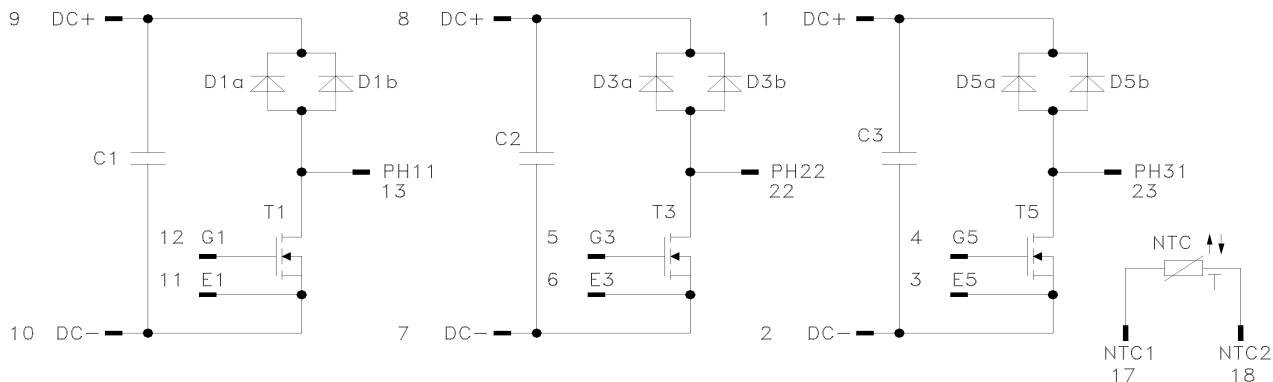
Version	Ordering Code	in DataMatrix as	in packaging barcode as
w/o thermal paste 12mm housing Press-fit pin	10-PZ123BA080ME-M909L18Y	M909L18Y	M909L18Y

Outline

Pin table		
Pin	X	Y
1	33,4	0
2	25,4	0
3	25,05	2,8
4	25,05	5,6
5	22,25	5,6
6	22,25	2,8
7	22,25	0
8	14,25	0
9	8	0
10	0	0
11	0	2,8
12	0	5,6
13	0	22,2
14	7,15	22,2
15	7,75	19,2
16	7,75	16,4
17	8,35	10,2
18	11,15	11,5
19	13,75	16,4
20	13,75	19,2
21	13,15	22,2
22	19,65	22,2
23	25,65	22,2
24	33,4	22,2
25	31,55	19,2
26	31,55	16,4



Pinout



Pin 15, 16, 19, 20, 25, 26 not connected

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